

**Applied Physics, Inc.** 

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## PSL Wafer Calibration Standards: 80nm to 3.040µm

Spot Depositions from 80nm to 1.112um Full Depositions: 80nm to 3.04um
PSL and NIST SRM Particle Size Standards
100mm 150mm 150mm 200mm & 200mm Vefore Prime Silicon

100mm, 150mm, 150mm, 200mm & 300mm Wafers, Prime Silicon 😽 KLA-Tencor: Surfscan SP1 Internal Version - [Scan] \_ 🗗 X Operation Data View Options Services Hel 01Aug2006 15:20:04 Dark Field Wide (Oblique Defects, Area Wafer ID: Lot ID: PSL 1UM Src / Dest : R 1 4 / Inspected Side: Front Recipe Name: 1UM R 1 Session Name : 1UM omment Throughput: Low 200 mm / 5.0 mm Oblique p DW u Full DN NA Gain W/N: 4.126E+000 / NA C Grade:Rejected DWO DNO DIC laze 100. NA NA NA NA 0 005 0.000 0.013 0.004 NA NA NA NA Ő StDev [ppm]: DWO Channel E um of All Defects LPD Count: 4649 Defect Density Area Cou 106 Total [mm<sup>2</sup>] 0.000 5 PD DWO [µmLSE] 960 0 800 0.832 3 0.832 0.8655 San 0.865 n 900-0.900 -0.936 0.936 0.974 0.974 1.013 13 1.013 -1.053 58 1.095 1146 1.095 1.139: 3044 1.185: 281 1.185 1.232: 30 Defects (Dark Field Wide (Oblique)) 1.282 3 1.232 1 09 1 11 1 12 1.282 1.333: 5 1.333 1.387 10 1.387 1.442 11 300 1.442 1.500 37 250 1.111 Std. Dev. 0.047 200 laze DWO [ppm] 100 100.0 Below Range 0.001 -0.002: 0.00

Ready

0.002

0.004

PSL Wafer Calibration Standards include:

0.00

1) NIST Traceable PSL Size Certificate based on NIST SRM size calibration

0

- 2) Post Wafer Scan on SP1 provided with color printout and PSL Size Certificate
- 3) Packaged in Single Wafer Carriers, bagged for shipping cleanliness
- 4) Each wafer standard, Single Wafer Carrier is labeled with deposition specifications

0.90

1.00

1.25

1.20 Пим

111M

1.30

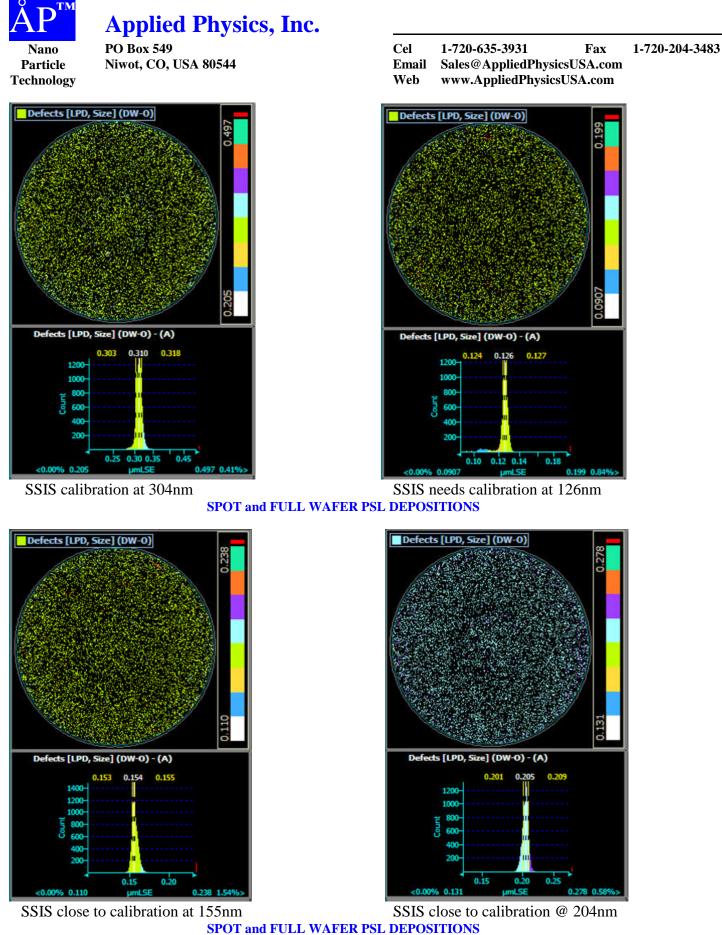
1.35

1.40

Unloaded (R. P1) Cass to Stn (S1)

1.45

5) <u>NIST SRM</u> Sizes of 101.8nm, 269nm and 895nm are also available



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